

## ISL28134

5V Ultra Low Noise, Auto-Zero Rail-to-Rail Precision Op Amp

FN6957 Rev.6.01 Mar 12, 2020

The ISL28134 is a single, auto-zeroing operational amplifier optimized for single and dual supply operation from 2.25V to 6.0V and  $\pm 1.125$ V and  $\pm 3.0$ V. The ISL28134 uses auto-zeroing circuitry to provide very low input offset voltage, drift and a reduction of the 1/f noise corner below 0.1Hz. The ISL28134 achieves ultra low offset voltage, offset temperature drift, wide gain bandwidth and rail-to-rail input/output swing while minimizing power consumption.

The ISL28134 is ideal for amplifying the sensor signals of analog front-ends that include pressure, temperature, medical, strain gauge and inertial sensors down to the  $\mu V$  levels.

The ISL28134 can be used over standard amplifiers with high stability across the industrial temperature range of -40°C to +85°C and the full industrial temperature range of -40°C to +125°C. The ISL28134 is available in an industry standard pinout SOIC and SOT-23 packages.

# **Applications**

- · Medical instrumentation
- · Sensor gain amps
- · Precision low drift, low frequency ADC drivers
- · Precision voltage reference buffers
- Thermopile, thermocouple, and other temperature sensors front-end amplifiers
- · Inertial sensors
- · Process control systems
- · Weight scales and strain gauge sensors

## **Features**

- · Rail-to-rail inputs and outputs
  - CMRR at  $V_{CM}$  = 0.1V beyond  $V_S$  ..................... 135dB, typ
- No 1/f noise corner down to 0.1Hz

  - 0.1Hz to 10Hz noise voltage...... 250nV<sub>P-P</sub>
- Low offset voltage . . . . . . . . . . . . . . . 2.5µV, Max
- Single supply .......2.25V to 6.0V
- Dual supply ..... ±1.125V to ±3.0V
   Low I<sub>CC</sub> ..... 675μA, typ
- Operating temperature range
- Packaging
  - Single: SOIC, SOT-23

## **Related Literature**

For a full list of related documents, visit our website:

• ISL28134 device page

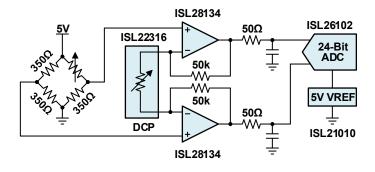


FIGURE 1. PRECISION WEIGH SCALE / STRAIN GAUGE

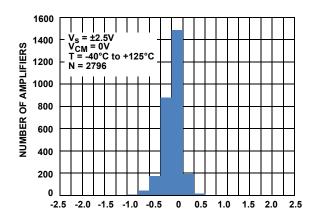
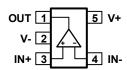
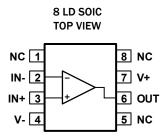


FIGURE 2.  $V_{OS}$  HISTOGRAM  $V_S = 5V$ 

# **Pin Configurations**

5 LD SOT-23 TOP VIEW





# **Pin Descriptions**

ISL28134 (8 Ld SOIC)	ISL28134 (5 Ld SOT-23)	PIN NAME	FUNCTION	EQUIVALENT CIRCUIT
2	4	IN-	Inverting input	(See Circuit 1)
3	3	IN+	Non-inverting input	IN+ O AN OSC  Circuit 1
4	2	V-	Negative supply	
6	1	OUT	Output	V+ OUT V- Circuit 2
7	5	V+	Positive supply	
1, 5, 8	-	NC	No Connect	Pin is floating. No connection made to IC.

# **Ordering Information**

PART NUMBER (Notes 2, 3)	PART MARKING	TEMP RANGE (°C)	TAPE AND REEL (Units) (Note 1)	PACKAGE (RoHS Compliant)	PKG. DWG. #
ISL28134IBZ	28134 IBZ	-40°C to +85°C	-	8 Ld SOIC	M8.15E
ISL28134IBZ-T13	28134 IBZ	-40°C to +85°C	2.5k	8 Ld SOIC	M8.15E
ISL28134IBZ-T7	28134 IBZ	-40°C to +85°C	1k	8 Ld SOIC	M8.15E
ISL28134IBZ-T7A	28134 IBZ	-40°C to +85°C	250	8 Ld SOIC	M8.15E
ISL28134FHZ-T7	BEEA (Note 4)	-40°C to +125°C	3k	5 Ld SOT-23	P5.064A
ISL28134FHZ-T7A	BEEA (Note 4)	-40°C to +125°C	250	5 Ld SOT-23	P5.064A
ISL28134ISENSEV1Z	Evaluation Board	1	ı		
ISL28134SOICEVAL1Z	Evaluation Board				

## NOTES:

- 1. See  $\underline{\mathsf{TB347}}$  for details about reel specifications.
- These Pb-free plastic packaged products employ special Pb-free material sets, molding compounds/die attach materials, and 100% matte tin plate plus
  anneal (e3 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations). Pb-free products are MSL
  classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J-STD-020.
- 3. For Moisture Sensitivity Level (MSL), see the ISL28134 device page. For more information about MSL, see TB363.
- 4. The part marking is located on the bottom of the part.



## **Absolute Maximum Ratings**

Supply Voltage V+ to V	
Input Differential Voltage	6.5V
Input Current	20mA
Voltage VOUT to GND (10s)	(V+) or (V-)
dv/dt Supply Slew Rate	100V/µs
ESD Rating	
Human Body Model (Tested per JED22-A114	lF)4kV
Machine Model (Tested per JED22-A115B) .	300V
Charged Device Model (Tested per JED22-C1	L10D) 2kV
Latch-up (Passed Per JESD78B)	+125°C

## **Thermal Information**

Thermal Resistance (Typical)	$\theta_{JA}$ (°C/W)	$\theta_{JC}$ (°C/W)
5 Ld SOT-23 (Notes 5, 6)	225	116
8 Ld SOIC (Notes 5, 6)	125	77.2
Maximum Storage Temperature Range	6	65°C to +150°C
Pb-Free Reflow Profile		see <u>TB493</u>

## **Operating Conditions**

Ambient Operating Temperature Range	
Industrial Grade Package	40°C to +85°C
Full Industrial Grade Package	40°C to +125°C
Operating Voltage Range	2.25V (±1.125V) to 6V (±3V)

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

#### NOTES:

- 5.  $\theta_{JA}$  is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief <u>TB379</u> for details.
- 6. For  $\theta_{\mbox{\scriptsize JC}}\!,$  the "case temp" location is taken at the package top center.

# **Electrical Specifications** $V_S = 5V$ , $V_{CM} = 2.5V$ , $T_A = +25^{\circ}C$ , unless otherwise specified. Boldface limits apply across the specified operating temperature range.

PARAMETER	DESCRIPTION	TEST CONDITIONS	MIN (Note 7)	ТҮР	MAX (Note 7)	UNITS
DC SPECIFICATIONS			·			
V <sub>OS</sub>	Input Offset Voltage		-2.5	-0.2	2.5	μV
		T <sub>A</sub> = -40°C to +85°C	-3.4	-	3.4	μV
		T <sub>A</sub> = -40°C to +125°C	-4	-	-4	μV
TCV <sub>OS</sub>	Input Offset Voltage Temperature Coefficient	T <sub>A</sub> = -40°C to +125°C	-15	-0.5	15	nV/°C
I <sub>B</sub>	Input Bias Current		-300	±120	300	pА
		T <sub>A</sub> = -40°C to +85°C	-300	-	300	pА
		T <sub>A</sub> = -40 ° C to +125 ° C	-550	-	550	pА
TCIB	Input Bias Current Temperature Coefficient	$T_A = -40$ °C to $+85$ °C	-	±1.4	-	pA/°C
		T <sub>A</sub> = -40°C to +125°C	-	±2	-	pA/°C
los	Input Offset Current		-600	±240	600	pА
		T <sub>A</sub> = -40°C to +85°C	-600	-	600	pА
		T <sub>A</sub> = -40 ° C to +125 ° C	-750	-	750	pА
TCIOS	Input Offset Current Temperature Coefficient	$T_A = -40$ °C to +85 °C	-	±2.8	-	pA/°C
		T <sub>A</sub> = -40°C to +125°C	-	±4	-	pA/°C
Common Mode Input Voltage Range		V+ = 5.0V, V- = 0V Guaranteed by CMRR	-0.1	-	5.1	V
CMRR	Common Mode Rejection Ratio	V <sub>CM</sub> = -0.1V to 5.1V	120	135	-	dB
		V <sub>CM</sub> = -0.1V to 5.1V	115	-	-	dB
PSRR	Power Supply Rejection Ratio	V <sub>S</sub> = 2.25V to 6.0V	120	135	-	dB
		V <sub>S</sub> = 2.25V to 6.0V	120	-	-	dB
V <sub>S</sub>	Supply Voltage (V+ to V-)	Guaranteed by PSRR	2.25	-	6.0	V



# **Electrical Specifications** $V_S = 5V$ , $V_{CM} = 2.5V$ , $T_A = +25$ °C, unless otherwise specified. Boldface limits apply across the specified operating temperature range. (Continued)

PARAMETER	DESCRIPTION	TEST CONDITIONS	MIN (Note 7)	TYP	MAX (Note 7)	UNITS
I <sub>S</sub>	Supply Current Per Amplifier	R <sub>L</sub> = OPEN	-	675	900	μΑ
		R <sub>L</sub> = OPEN T <sub>A</sub> = -40°C to +85°C	-	-	1075	μΑ
		R <sub>L</sub> = OPEN T <sub>A</sub> = -40°C to +125°C	-	-	1150	μА
I <sub>SC</sub>	Short Circuit Output Source Current	R <sub>L</sub> = Short to V-	-	65	-	mA
	Short Circuit Output Sink Current	R <sub>L</sub> = Short to V+	-	-65	-	mA
V <sub>OH</sub>	Output Voltage Swing, HIGH	$R_L = 10k\Omega$ to $V_{CM}$	15	10	-	mV
	From V <sub>OUT</sub> to V <sub>+</sub>	$R_L = 10k\Omega$ to $V_{CM}$	15	-	-	mV
V <sub>OL</sub>	Output Voltage Swing, LOW	$R_L = 10k\Omega$ to $V_{CM}$	-	10	15	mV
	From V <sub>-</sub> to V <sub>OUT</sub>	$R_L = 10k\Omega$ to $V_{CM}$	-	-	15	mV
A <sub>OL</sub>	Open Loop Gain	$R_L = 1M\Omega$	-	174	-	dB
AC SPECIFICATIONS						
C <sub>IN</sub> Input Capacitance	Input Capacitance	Differential	-	5.2	-	pF
		Common Mode	-	5.6	-	pF
e <sub>N</sub>	Input Noise Voltage	f = 0.1Hz to 10Hz	-	250	400	nV <sub>P-P</sub>
		f = 10Hz	-	8	-	nV/√Hz
		f = 1kHz	-	10	-	nV/√Hz
I <sub>N</sub>	Input Noise Current	f = 1kHz	-	200	-	fA/√Hz
GBWP	Gain Bandwidth Product		-	3.5	-	MHz
EMIRR	EMI Rejection Ratio	A <sub>V</sub> = +1, V <sub>IN</sub> = 200mV <sub>p-p</sub> , V <sub>CM</sub> = 0V, V+ = 2.5V, V- = -2.5V	-	75	-	dB
TRANSIENT RESPON	ISE				I	
SR	Positive Slew Rate	$V+ = 5V$ , $V- = 0V$ , $V_{OUT} = 1V$ to $3V$ , $R_L = 100k\Omega$ ,	-	1.5	-	V/µs
	Negative Slew Rate	C <sub>L</sub> = 3.7pF	-	1.0	-	V/µs
t <sub>r</sub> , t <sub>f</sub> , Small Signal	Rise Time, t <sub>r</sub> 10% to 90%	$V+ = 5V, V- = 0V, V_{OUT} = 0.1V_{P-P}, R_F = 0\Omega,$	-	0.07	-	μs
	Fall Time, t <sub>f</sub> 10% to 90%	$R_L = 100k\Omega, C_L = 3.7pF$	-	0.17	-	μs
t <sub>r</sub> , t <sub>f</sub> Large Signal	Rise Time, t <sub>r</sub> 10% to 90%	$V+ = 5V, V- = 0V, V_{OUT} = 2V_{P-P}, R_F = 0\Omega,$	-	1.3	-	μs
	Fall Time, t <sub>f</sub> 10% to 90%	$R_L = 100k\Omega, C_L = 3.7pF$	-	2.0	-	μs
t <sub>s</sub>	Settling Time to 0.1%, 2V <sub>P-P</sub> Step	$A_V = -1$ , $R_F = 1k\Omega$ , $C_L = 3.7pF$	-	100	-	μs
t <sub>recover</sub>	Output Overload Recovery Time, Recovery to 90% of Output Saturation	$A_V = +2$ , $R_F = 10k\Omega$ , $R_L = 100k$ , $C_L = 3.7pF$	-	3.1	-	μs
V <sub>OS</sub>	Input Offset Voltage		-2.5	-0.2	2.5	μV
		$T_A = -40$ °C to +85 °C	-3.4	-	3.4	μV
		T <sub>A</sub> = -40 ° C to +125 ° C	-4	-	-4	μV
TCV <sub>OS</sub>	Input Offset Voltage Temperature Coefficient	T <sub>A</sub> = -40°C to +125°C	-15	-0.5	15	nV/°C



# **Electrical Specifications** $V_S = 2.5V$ , $V_{CM} = 1.25V$ , $T_A = +25$ °C, unless otherwise specified. **Boldface limits apply over the specified** operating temperature range.

PARAMETER	DESCRIPTION	TEST CONDITIONS	MIN ( <u>Note 7</u> )	TYP	MAX (Note 7)	UNITS
DC SPECIFICATIONS			*		*	*
I <sub>B</sub>	Input Bias Current		-300	±120	300	pА
		$T_A = -40$ °C to +85 °C	-300	-	300	pА
		T <sub>A</sub> = -40°C to +125°C	-550	-	550	pА
TCIB	Input Bias Current Temperature	$T_A = -40$ °C to +85 °C	-	±1.4	-	pA/°C
	Coefficient	T <sub>A</sub> = -40°C to +125°C	-	±2	-	pA/°C
I <sub>OS</sub>	Input Offset Current		-600	±240	600	pА
		$T_A = -40$ °C to +85 °C	-600	-	600	pА
		T <sub>A</sub> = -40°C to +125°C	-750	-	750	pА
TCI <sub>OS</sub>	Input Offset Current Temperature	$T_A = -40 ^{\circ}\text{C to} + 85 ^{\circ}\text{C}$	-	±2.8	-	pA/°C
	Coefficient	$T_A = -40$ °C to +125 °C	-	±4	-	pA/°C
Common Mode Input Voltage Range		V+ = 2.5V, V- = 0V Guaranteed by CMRR	-0.1	-	2.6	V
CMRR	Common Mode Rejection Ratio	V <sub>CM</sub> = -0.1V to 2.6V	120	135	-	dB
		V <sub>CM</sub> = -0.1V to 2.6V	115	-	-	dB
I <sub>S</sub>	Supply Current per Amplifier	R <sub>L</sub> = OPEN	-	715	940	μΑ
		$R_L = OPEN$ $T_A = -40$ °C to +85 °C	-	-	1115	μΑ
		R <sub>L</sub> = OPEN T <sub>A</sub> = -40°C to +125°C	-	-	1190	μΑ
I <sub>SC</sub>	Short Circuit Output Source Current	R <sub>L</sub> = Short to Ground	-	65	-	mA
	Short Circuit Output Sink Current	R <sub>L</sub> = Short to V+	-	-65	-	mA
V <sub>OH</sub>	Output Voltage Swing, HIGH	$R_L = 10k\Omega$ to $V_{CM}$	15	10	-	mV
	From V <sub>OUT</sub> to V <sub>+</sub>	$R_L = 10k\Omega$ to $V_{CM}$	15	-	-	m۷
V <sub>OL</sub>	Output Voltage Swing, LOW	$R_L = 10k\Omega$ to $V_{CM}$	-	10	15	mV
	From V₋ to V <sub>OUT</sub>	$R_L = 10k\Omega$ to $V_{CM}$	-	-	15	m۷
AC SPECIFICATIONS					I	
C <sub>IN</sub>	Input Capacitance	Differential	-	5.2	-	pF
		Common Mode	-	5.6	-	pF
e <sub>N</sub>	Input Noise Voltage	f = 0.1Hz to 10Hz	-	250	400	nV <sub>P-P</sub>
		f = 10Hz	-	8	-	nV/√Hz
		f = 1kHz	-	10	-	nV/√Hz
I <sub>N</sub>	Input Noise Current	f = 1kHz	-	200	-	fA/√Hz
GBWP	Gain Bandwidth Product		-	3.5	-	MHz

# **Electrical Specifications** $V_S = 2.5V$ , $V_{CM} = 1.25V$ , $T_A = +25$ °C, unless otherwise specified. Boldface limits apply over the specified operating temperature range. (Continued)

PARAMETER	DESCRIPTION	TEST CONDITIONS	MIN (Note 7)	ТҮР	MAX (Note 7)	UNITS
TRANSIENT RESPON	SE					
SR	Positive Slew Rate	V+ = 2.5V, V- = 0V, V <sub>OUT</sub> = 0.25V to 2.25V,	-	1.5	-	V/µs
	Negative Slew Rate	$R_L = 100k\Omega, C_L = 3.7pF$	-	1.0	-	V/µs
t <sub>r</sub> , t <sub>f</sub> , Small Signal	Rise Time, t <sub>r</sub> 10% to 90%	V+ = 2.5V, V- = 0V, V <sub>OUT</sub> = 0.1V <sub>P-P</sub> ,	-	0.07	-	μs
	Fall Time, t <sub>f</sub> 10% to 90%	$R_F = 0\Omega$ , $R_L = 100k\Omega$ , $C_L = 3.7pF$	-	0.17	-	μs
t <sub>r</sub> , t <sub>f</sub> Large Signal	Rise Time, t <sub>r</sub> 10% to 90%	$V+ = 2.5V$ , $V- = 0V$ , $V_{OUT} = 2V_{P-P}$ , $R_F = 0\Omega$ ,	-	1.3	-	μs
	Fall Time, t <sub>f</sub> 10% to 90%	$R_L = 100k\Omega, C_L = 3.7pF$	-	2.0	-	μs
t <sub>s</sub>	Settling Time to 0.1%, 2V <sub>P-P</sub> Step	$A_V = -1$ , $R_F = 1k\Omega$ , $C_L = 3.7pF$	-	100	-	μs
t <sub>recover</sub>	Output Overload Recovery Time, Recovery to 90% of Output Saturation	$A_V = +2$ , $R_F = 10k\Omega$ , $R_L = 100k$ , $C_L = 3.7pF$	-	1.5	-	μs

#### NOTE:

# Typical Performance Curves $T_A = +25$ °C, $V_{CM} = 0$ V Unless otherwise specified.

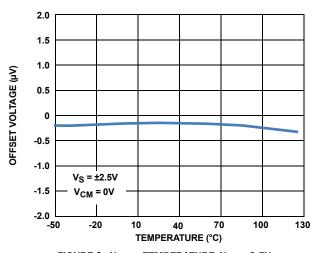


FIGURE 3.  $V_{OS}$  vs TEMPERATURE,  $V_S = \pm 2.5V$ 

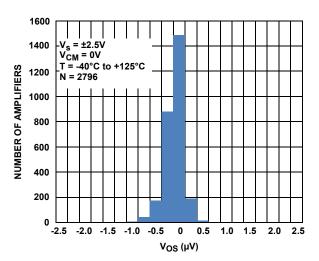


FIGURE 5.  $V_{OS}$  HISTOGRAM  $V_S = 5V$ 

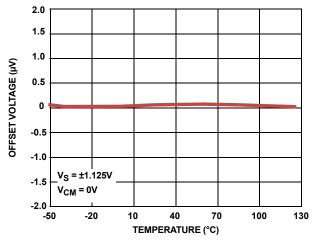


FIGURE 4.  $V_{OS}$  vs TEMPERATURE,  $V_S = \pm 1.125V$ 

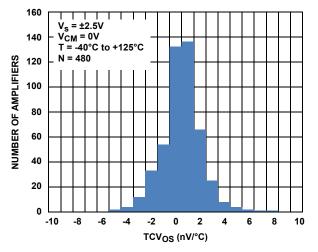


FIGURE 6. TCV<sub>OS</sub> HISTOGRAM V<sub>S</sub> = 5V

<sup>7.</sup> Compliance to datasheet limits is assured by one or more methods: production test, characterization and/or design.

# Typical Performance Curves $T_A = +25 \,^{\circ}$ C, $V_{CM} = 0$ V Unless otherwise specified. (Continued)

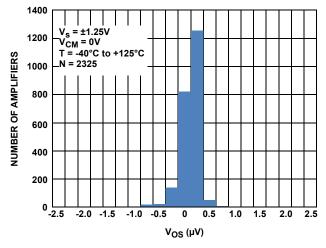


FIGURE 7.  $V_{OS}$  HISTOGRAM  $V_S = 2.5V$ 

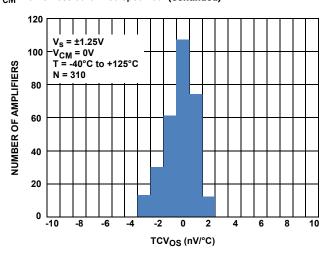


FIGURE 8.  $TCV_{OS}$  HISTOGRAM  $V_S = 2.5V$ 

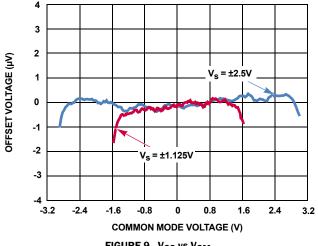


FIGURE 9. VOS vs VCM

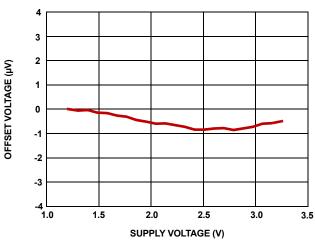


FIGURE 10.  $V_{OS}$  vs SUPPLY VOLTAGE

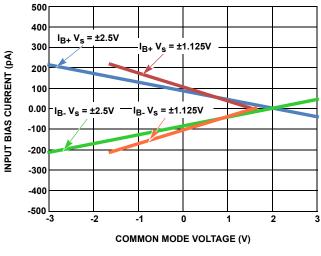


FIGURE 11. IB vs VCM

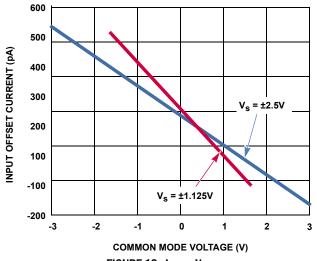


FIGURE 12.  $I_{OS}$  vs  $V_{CM}$ 

# Typical Performance Curves T<sub>A</sub> = +25 °C, V<sub>CM</sub> = 0V Unless otherwise specified. (Continued)

350

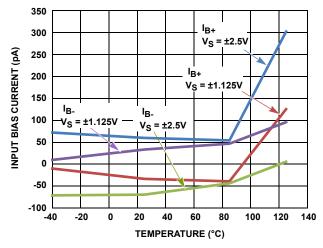
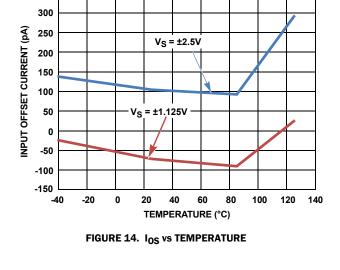


FIGURE 13. IB vs TEMPERATURE



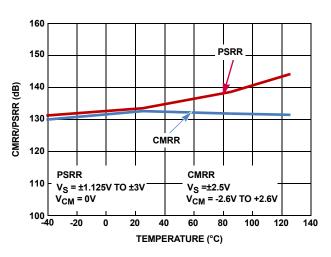


FIGURE 15. CMRR and PSRR vs TEMPERATURE

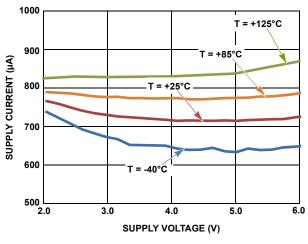


FIGURE 16. SUPPLY CURRENT vs SUPPLY VOLTAGE

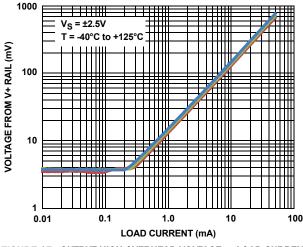


FIGURE 17. OUTPUT HIGH OVERHEAD VOLTAGE vs LOAD CURRENT

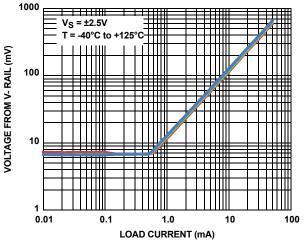


FIGURE 18. OUTPUT LOW OVERHEAD VOLTAGE vs LOAD CURRENT

# **Typical Performance Curves** $T_A = +25 \,^{\circ}\text{C}$ , $V_{CM} = 0V$ Unless otherwise specified. (**Continued**)

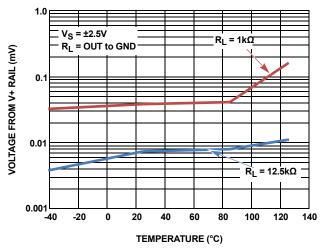


FIGURE 19. V<sub>OH</sub> vs TEMPERATURE

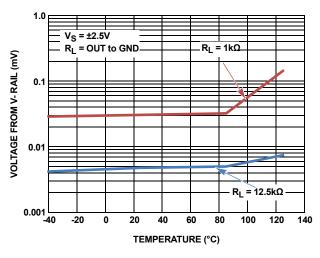


FIGURE 20.  $V_{OL}$  vs TEMPERATURE

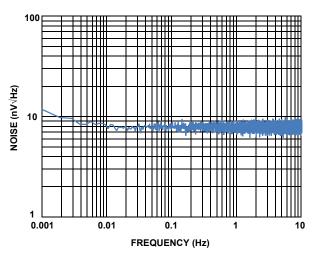


FIGURE 21. INPUT NOISE VOLTAGE DENSITY vs FREQUENCY

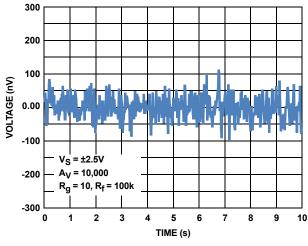


FIGURE 22. INPUT NOISE VOLTAGE 0.1Hz TO 10Hz

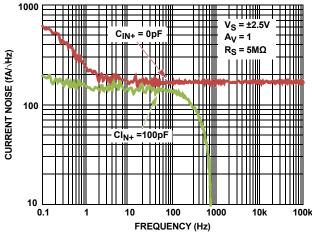


FIGURE 23. INPUT NOISE CURRENT DENSITY vs FREQUENCY

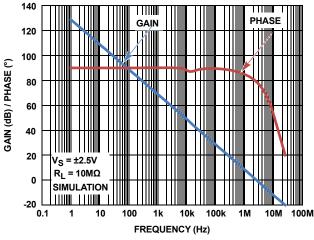


FIGURE 24. OPEN LOOP GAIN AND PHASE,  $R_L = 10M$ 

# Typical Performance Curves $\tau_A = +25 \,^{\circ} \, \text{C}$ , $V_{\text{CM}} = 0 \,^{\circ} \, \text{Unless otherwise specified.}$ (Continued)

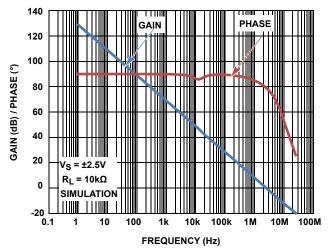


FIGURE 25. OPEN LOOP GAIN AND PHASE,  $R_L = 10k$ 

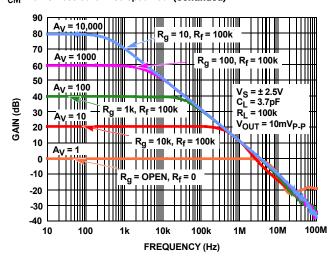


FIGURE 26. FREQUENCY RESPONSE vs CLOSED LOOP GAIN

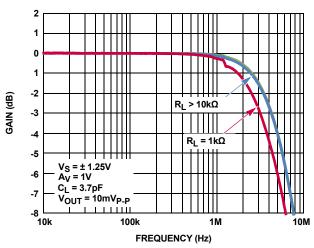


FIGURE 27. GAIN vs FREQUENCY vs  $R_{L_1} V_S = 2.5V$ 

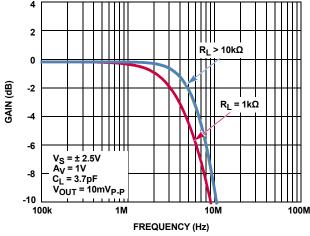


FIGURE 28. GAIN vs FREQUENCY vs  $R_{L_1} V_S = 5.0V$ 

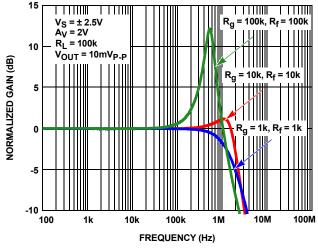


FIGURE 29. GAIN vs FREQUENCY vs FEEDBACK RESISTOR VALUES  $R_{f}/R_{g}$ 

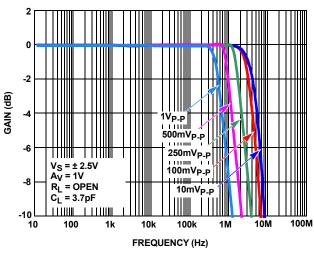


FIGURE 30. GAIN vs FREQUENCY vs Vout

# Typical Performance Curves $T_A = +25 \,^{\circ} \, C$ , $V_{CM} = 0 \,^{\circ} \, U$ Unless otherwise specified. (Continued)

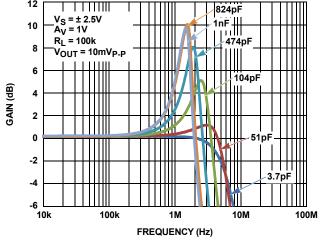


FIGURE 31. GAIN vs FREQUENCY vs CL

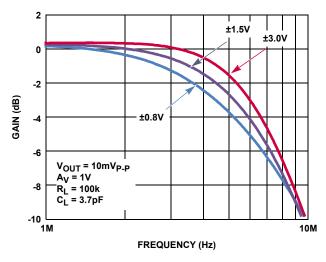


FIGURE 32. GAIN vs FREQUENCY vs SUPPLY VOLTAGE

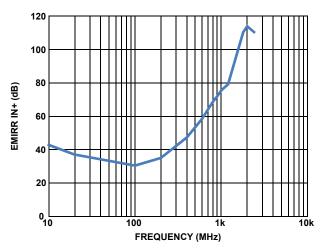


FIGURE 33. EMIRR AT IN+ PIN vs FREQUENCY

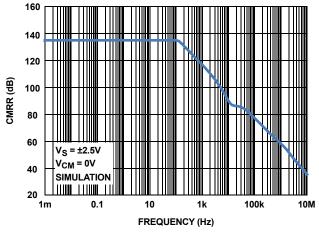


FIGURE 34. CMRR vs FREQUENCY,  $V_S = 5V$ 

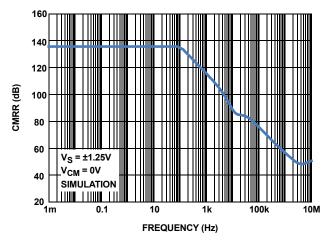


FIGURE 35. CMRR vs FREQUENCY, V<sub>S</sub> = 2.5V



# Typical Performance Curves T<sub>A</sub> = +25 °C, V<sub>CM</sub> = 0V Unless otherwise specified. (Continued)

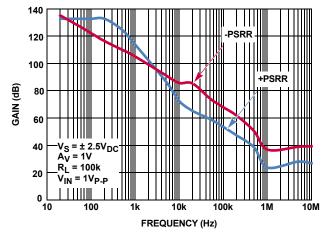


FIGURE 36. PSRR vs FREQUENCY,  $V_S = 5V$ 

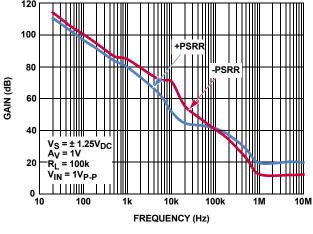


FIGURE 37. PSRR vs FREQUENCY, V<sub>S</sub> = 2.5V

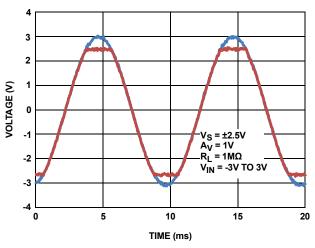


FIGURE 38. NO PHASE INVERSION

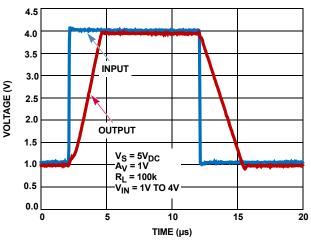


FIGURE 39. LARGE SIGNAL STEP RESPONSE (3V)

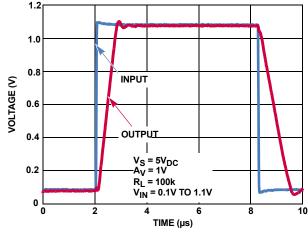


FIGURE 40. LARGE SIGNAL STEP RESPONSE (1V)

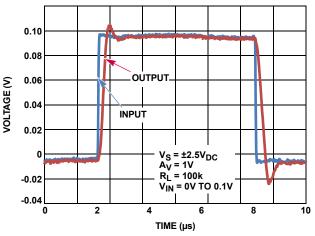


FIGURE 41. SMALL SIGNAL STEP RESPONSE (100mV)

# Typical Performance Curves $T_A = +25$ °C, $V_{CM} = 0$ V Unless otherwise specified. (Continued)

55

50

45

40

35

30

25

20

15

10

OVERSHOOT (%)

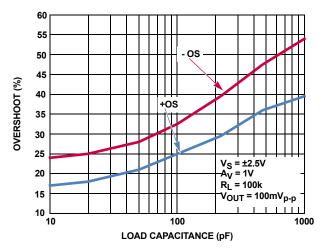


FIGURE 42. SMALL SIGNAL OVERSHOOT vs LOAD CAPACITANCE,  $VS = \pm 2.5V$ 

# 10 100 1000 LOAD CAPACITANCE (pF) FIGURE 43. SMALL SIGNAL OVERSHOOT vs LOAD CAPACITANCE,

+OS

os

 $V_S = \pm 1.25 V$ 

 $V_{OUT} = 100 \text{mV}_{p-p}$ 

 $A_V = 1V$ 

R<sub>L</sub> = 100k

# V<sub>S</sub> = ±1.25V

# **Applications Information**

## **Functional Description**

The ISL28134 is a single 5V rail-to-rail input/output amplifier that operates on a single or dual supply. The ISL28134 uses a proprietary auto-zeroing technique that combines a 3.5MHz main amplifier with a very high open loop gain (174dB) offset-nulling amplifier to achieve very low offset voltage and drift (0.2µV, 0.5nV/°C) while having a low supply current (675µA). The very low 1/f noise corner <0.1Hz and low input noise voltage (8nV/ $\sqrt{\text{Hz}}$  at 100Hz) of the amplifier makes it ideal for low frequency precision applications requiring very high gain and low noise.

This multi-path amplifier architecture contains a time continuous main amplifier whose input DC offset is corrected by a parallel-connected, high gain offset-nulling DC correction amplifier operating at 100kHz. From DC to ~10kHz, both amplifiers are active with the DC offset correction active with most of the low frequency gain provided by the nulling amplifier. A 10kHz crossover filter cuts off the low frequency nulling amplifier path leaving the main amplifier active out to the -3dB frequency (3.5MHz GBWP).

The key benefits of this architecture for precision applications are rail-to-rail inputs/outputs, high open loop gain, low DC offset and temperature drift, low 1/f noise corner and low input noise voltage. The noise is virtually flat across the frequency range from a few MHz out to 100kHz, except for the narrow noise peak at the amplifier crossover frequency (10kHz).

## **Power Supply Considerations**

The ISL28134 features a wide supply voltage operating range. The ISL28134 operates on single (+2.25V to +6.0V) or dual (±1.125 to ±3.0V) supplies. Power supply voltages greater than the +6.5V absolute maximum (specified in the "Absolute Maximum Ratings" on page 4) can permanently damage the device. Performance of the device is optimized for supply voltages greater than 2.5V. This makes the ISL28134 ideal for portable 3V battery applications that require the precision performance. It is highly recommended that a

 $0.01\mu F$  or larger high frequency decoupling capacitor is placed across the power supply pins of the IC to maintain high performance of the amplifier.

## Rail-to-rail Input and Output (RRIO)

Unlike some amplifiers whose inputs may not be taken to the power supply rails or whose outputs may not drive to the supply rails, the ISL28134 features rail-to-rail inputs and outputs. This allows the amplifier inputs to have a wide common mode range (100mV beyond supply rails) while maintaining high CMRR (135dB) and maximizes the signal to noise ratio of the amplifier by having the  $V_{\mbox{OH}}$  and  $V_{\mbox{OL}}$  levels be at the V+ and V- rails, respectively.

#### **Low Input Voltage Noise Performance**

In precision applications, the input noise of the front end amplifier is a critical parameter. Combined with a high DC gain to amplify the small input signal, the input noise voltage will result in an output error in the amplifier. A  $1\mu V_{P.P}$  input noise voltage with an amplifier gain of 10,000V/V will result in an output offset in the range of 10mV, which can be an unacceptable error source. With only  $250\text{nV}_{P.P}$  at the input, along with a flat noise response down to 0.1Hz, the ISL28134 can amplify small input signals with minimal output error.

The ISL28134 has the lowest input noise voltage compared to other competitor's Auto-Zero amplifiers with similar supply currents (see Table 1). The overall input referred voltage noise of an amplifier can be expressed as a sum of the input noise voltage, input noise current of the amplifier and the Johnson noise of the gain-setting resistors used. The product of the input noise current and external feedback resistors along with the Johnson noise, increases the total output voltage noise as the value of the resistance goes up. For optimizing noise performance, choose lower value feedback resistors to minimize the effect of input noise current. Although the ISL28134 features a very low  $200f\text{A}/\sqrt{\text{Hz}}$  input noise current, at source impedances  $>100k\Omega$ , the input referred noise voltage will be dominated by the input current noise. Keep source input impedances under  $10k\Omega$  for optimum performance.



TΛ	D	_	4

PART	VOLTAGE NOISE AT 100Hz	0.1Hz TO 10Hz PEAK-TO-PEAK VOLTAGE NOISE
Competitor A	22nV/√Hz	600nV <sub>P-P</sub>
Competitor B	16nV/√Hz	260nV <sub>P-P</sub>
Competitor C	90nV/√Hz	1500nV <sub>P-P</sub>
ISL28134	8nV/√Hz	250nV <sub>P-P</sub>

## **High Source Impedance Applications**

The input stage of auto-zero amplifiers do not behave like conventional amplifier input stages. The ISL28134 uses switches that continually sample the nulling amplifier input at 100kHz to reduce the input offset to  $1\mu V$ . The dynamic behavior of these switches induces a charge injection current to the input terminals of the amplifier. The charge injection current has a DC path to ground through the resistances seen at the input terminals of the amplifier. Higher input impedance cause an apparent shift in the input bias current of the amplifier. Input impedances larger than  $10k\Omega$  begin to have significant increases in the bias currents. To minimize the effect of impedance on input bias currents, an input resistance of  $<10k\Omega$  is recommended.

Because the nulling amplifier has charge injection currents at each terminal, the input impedance should be balanced across each input (see Figure 44). The input impedance of the amplifier should be matched between the IN+ and IN- terminals to minimize total input offset current. Input offset currents show up as an additional output offset voltage, as shown in Equation 1:

$$V_{OSTOT} = V_{OS} - R_F * I_{OS}$$
 (EQ. 1)

If the offset voltage of the amplifier is negative, the input offset currents will add to the total output offset. For a 10,000V/V gain amplifier using 1M $\Omega$  feedback resistor, a 500pA total input offset current will have an additional output offset voltage of 0.5mV. By keeping the input impedance low and balanced across the amplifier inputs, the input offset current is kept below 100pA, resulting in an offset voltage 0.1mV or less.

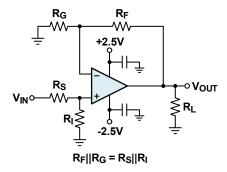


FIGURE 44. CIRCUIT IMPLEMENTATION FOR REDUCING INPUT BIAS CURRENTS

#### IN+ and IN- Protection

The ISL28134 is capable of driving the input terminals up to and beyond the supply rails by about 0.5V. Back biased ESD diodes from the input pins to the V+ and V- rails will conduct current when the input signals go more than 0.5V beyond the rail (see Figure 45). The ESD protection diodes must be current limited to 20mA or less to prevent damage of the IC. This current can be reduced by placing a resistor in series with the IN+ and IN- inputs in the event the input signals go beyond the rail.

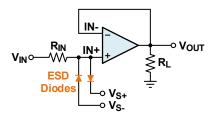


FIGURE 45. INPUT CURRENT LIMITING

## **EMI Rejection**

Electromagnetic Interference (EMI) can be a problem in high frequency applications for precision amplifiers. The op amp pins are susceptible to EMI signals which can rectify high frequency inputs beyond the amplifier bandwidth and present itself as a shift in DC offset voltage. Long trace leads to op amp pins may act as an antenna for radiated RF signals, which result in a total conductive EMI noise into the op amp inputs.

The most susceptible pin is the non-inverting IN+ input therefore, EMI rejection (EMIR) on this pin is important for RF type applications. The ability of the amplifier output to reject EMI is called EMI Rejection Ratio (EMIRR) and is computed as:

EMIRR (dB) = 20 log (
$$V_{IN}$$
 PEAK/ $\Delta V_{OS}$ 

The test circuit for measuring the DC offset of the amplifier with an RF signal input to the IN+ pin is shown in Figure 46. The EMIRR performance of the ISL28134 at the IN+ pin across a frequency of 10MHz to 2.4GHz is plotted on Figure 33. The ISL28134 shows a typical EMIRR of 75dB at 1GHz. For better EMI immunity, a small RFI filter can be placed at the input to attenuate out of band signals and reduce DC offset shift from high frequency RF signals into the IN+ pin. For example, a  $15\Omega$  and 100pF RC filter will roll off signals above 100MHz for better EMIRR performance.

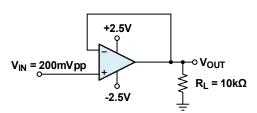


FIGURE 46. CIRCUIT TESTING EMIRR

## **Output Phase Reversal**

The Output phase reversal is the unexpected inversion of the amplifier output signal when the inputs exceed the common mode input range. Since the ISL28134 is a rail-to-rail input amplifier, the ISL28134 is specifically designed to prevent output phase reversal within its common mode input range. In fact, the ISL28134 will not phase invert even when the input signals go 0.5V beyond the supply rails (see <a href="Figure 38">Figure 38</a>). If input signals are expected to go beyond the rails, it is highly recommended to minimize the forward biased ESD diode current to prevent phase inversion by placing a resistor in series with the input.

## **High Gain, Precision DC-Coupled Amplifier**

Precision applications that need to amplify signals in the range of a few  $\mu V$  require gain in the order of thousands of V/V to get a good signal to the Analog to Digital Converter (ADC). This can be achieved by using a very high gain amplifier with the appropriate open loop gain and bandwidth.

In addition to the high gain and bandwidth, it is important that the amplifier have low  $V_{OS}$  and temperature drift along with a low input noise voltage. For example, an amplifier with  $100\mu V$  offset voltage and  $0.5\mu V/\,^{\circ}C$  offset drift configured in a closed loop gain of  $10,\!000V/V$  would produce an output error of 1V and a  $5mV/\,^{\circ}C$  temperature dependent error. Unless offset trimming and temperature compensation techniques are used, this error makes it difficult to resolve the input voltages needed in the precision application.

The ISL28134 features a low  $V_{OS}$  of  $\pm 4\mu V$  max and a very stable  $10nV/^{\circ}C$  max temperature drift, which produces an output error of only  $\pm 40mV$  and a temperature error of  $0.1mV/^{\circ}C$ . With an ultra low input noise of  $210nV_{P-P}$  (0.1Hz to 10Hz) and no 1/f corner frequency, the ISL28134 is capable of amplifying signals in the  $\mu V$  range with high accuracy. For even further DC precision, some feedback filtering  $C_F$  (see Figure 47) to reduce the noise can be implemented as a total signal stage amplifier. As a method of best practice, the ISL28134 should be impedance matched at the two input terminals. A balancing capacitor of the same value at the on-inverting terminal will result in the amplifier input impedances tracking across frequency

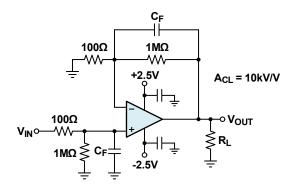


FIGURE 47. HIGH GAIN, PRECISION DC-COUPLED AMPLIFIER

#### **ISL28134 SPICE Model**

Figure 48 shows the SPICE model schematic and Figure 49 shows the net list for the SPICE model. The model is a simplified version of the actual device and simulates important AC and DC parameters. The AC parameters incorporated into the model are: 1/f and flat band noise voltage, slew rate, CMRR, and gain and phase. The DC parameters are 1/f0, 1/f0, total supply current, output voltage swing and output current limit (65mA). The model uses typical parameters given in the "Electrical Specifications" table beginning on page 4. The AVOL is adjusted for 174dB with the dominant pole at 6.5mHz. The CMRR is set at 135dB, 1/f1 = 200Hz. The input stage models the actual device to present an accurate AC representation. The model is configured for an ambient temperature of +25°C.

<u>Figures 50</u> through <u>63</u> show the characterization vs simulation results for the noise voltage, open loop gain phase, closed loop gain vs frequency, CMRR, large signal 3V step response, large signal 1V step response, and output voltage swing  $V_{OH}/V_{OL}$  ±2.5V supplies (no phase inversion).

#### **LICENSE STATEMENT**

The information in the SPICE model is protected under United States copyright laws. Intersil Corporation hereby grants users of this macro-model, hereto referred to as "Licensee", a nonexclusive, nontransferable license to use this model, as long as the Licensee abides by the terms of this agreement. Before using this Macro-Model, the Licensee should read this license. If the Licensee does not accept these terms, permission to use the model is not granted.

The Licensee may not sell, loan, rent, or license the macro-model, in whole, in part, or in modified form, to anyone outside the Licensee's company. The Licensee may modify the Macro-Model to suit his/her specific applications, and the Licensee may make copies of this Macro-Model for use within their company only.

This Macro-Model is provided "AS IS, WHERE IS, AND WITH NO WARRANTY OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE."

In no event will Intersil be liable for special, collateral, incidental, or consequential damages in connection with or arising out of the use of this Macro-Model. Intersil reserves the right to make changes to the product and the Macro-Model without prior notice.



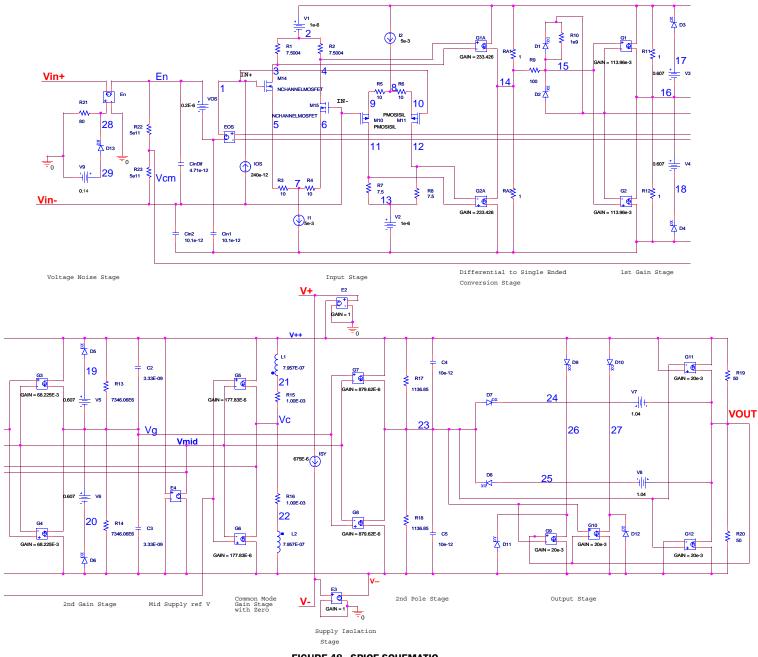


FIGURE 48. SPICE SCHEMATIC

*ISL28134 Macromodel	*	G_G6 V VC VCM VMID 177.83E-6
*	*Input Stage	E_EOS 1 30 VC VMID 1
*Revision History:	M_M10 11 VIN- 9 9 PMOSISIL	R_R15 VC 21 1.00E-03
* Revision A, LaFontaine June 17th 2011	_	_
·	M_M11 12 1 10 10 PMOSISIL	R_R16
* Model for Noise, quiescent supply currents,	M_M14 3 1 5 5 NCHANNELMOSFET	R_R22 EN VCM 5e11
*CMRR135dB f = 200Hz, AVOL 174dB f =	M_M15 4 VIN- 6 6 NCHANNELMOSFET	R_R23 VCM VIN- 5e11
*6.5mHz, $SR = 1.5V/us$ , $GBWP 3.5MHz$ .	I_I1 7 V DC 5e-3	L_L1 21 V++ 7.957E-07
*Copyright 2011 by Intersil Corporation	I_I2 V++ 8 DC 5e-3	_ L_L2
*Refer to data sheet "LICENSE STATEMENT"	_	*
*Use of this model indicates your acceptance	I_IOS VIN- 1 DC 240e-12	
*with the terms and provisions in the License	G_G1A V++ 14 4 3 233.4267	*2nd Pole Stage
·	G_G2A V 14 11 12 233.4267	G_G7 V++ 23 VG VMID 879.62E-6
*Statement.	V_V1 V++ 2 1e-6	G_G8 V 23 VG VMID 879.62E-6
*		
*Intended use:	V_VOS EN 30 0.2E-6	R_R18 V 23 1136.85
*This Pspice Macromodel is intended to give		_
*typical DC and AC performance	R_R1 3 2 7.5004	C_C4 23 V++ 10e-12
*characteristics under a wide range of	R_R2 4 2 7.5004	C_C5 V 23 10e-12
*external circuit configurations using	R_R3 5 7 10	*
*compatible simulation platforms – such as	R_R4 7 6 10	*Output Stage
*iSim PE.	R_R5 98 10	G_G9 26 V VOUT 23 20e-3
*	_	<del>_</del>
*Device performance features supported by	R_R6 8 10 10	G_G10 27 V 23 VOUT 20e-3
*this model:	R_R7 13 11 7.5	G_G11 VOUT V++ V++ 23 20e-3
	R_R8 13 12 7.5	G_G12
*Typical, room temp., nominal power supply		
*voltages used to produce the following	R_RA2 V 14 1	V_V8 VOUT 25 1.04
*characteristics:	_	_
*Open and closed loop I/O impedances,	C_CinDif VIN- EN 4.71e-12	D_D7 23 24 DX
*Open loop gain and phase,	C_Cin1 V 30 10.1e-12	D_D8 25 23 DX
	C_Cin2 V VIN- 10.1e-12	D_D9 V++ 26 DX
*Closed loop bandwidth and frequency	*	D_D10 V++ 27 DX
*response,	*1st Gain Stage	 D_D11
*Loading effects on closed loop frequency	G_G1 V++ 16 15 VMID 113.96e-3	_
*response,	<del>-</del>	D_D12 V 27 DY
*Input noise terms including 1/f effects,	G_G2 V 16 15 VMID 113.96e-3	R_R19 VOUT V++ 50
	V_V3 17 16 0.607	R_R20 V VOUT 50
*Slew rate, Input and Output Headroom limits	V_V4 16 18 0.607	*
*to I/O voltage swing, Supply current at	D_D1 15 VMID DX	.model pmosisil pmos (kp=16e-3 vto=-0.6
*nominal specified supply voltages,	D_D2 VMID 15 DX	+kf=0 af=1)
*Output current limiting (65mA)	—	•
*	D_D3	.model NCHANNELMOSFET nmos (kp=3e-3
*Device performance features NOT	D_D4 V 18 DX	+vto=0.6 kf=0 af=1)
*supported by this model:	R_R9 15 14 100	.model DN D(KF=6.69e-9 af=1)
*Harmonic distortion effects,	R_R10	.MODEL DX D(IS=1E-12 Rs=0.1 kf=0 af=1)
*Disable operation (if any),	R_R11	.MODEL DY D(IS=1E-15 BV=50 Rs=1 kf=0
*Thermal effects and/or over temperature	R_R12 V 16 1	+af=1)
•	K_K1Z V- 10 1	.ends ISL28134
*parameter variation,	***************************************	
*Performance variation vs. supply voltage,	*2nd Gain Stage	
*Part to part performance variation due to	G_G3 V++ VG 16 VMID 68.225E-3	
*normal process parameter spread,	G_G4 V VG 16 VMID 68.225E-3	
*Any performance difference arising from	V_V5 19 VG 0.607	
, .	V_V6 VG 20 0.607	
*different packaging,	<del>-</del>	
*Load current reflected into the power supply	D_D5	
*current.	D_D6 V 20 DX	
* source ISL28134	R_R13 VG V++ 7346.06E6	
*	R_R14 V VG 7346.06E6	
* Connections: Linnut	C_C2 VG V++ 3.33E-09	
* Connections: +input		
*   -input	C_C3 V VG 3.33E-09	
*   +Vsupply	•	
*     -Vsupply	*Mid supply Ref	
*       output	E_E4 VMID V V++ V 0.5	
*	*	
.subckt ISL28134 Vin+ Vin- V+ V- VOUT	*Cumply location Ctore	
*	*Supply Isolation Stage	
*Valtaga Najag	E_E2 V++ 0 V+ 0 1	
*Voltage Noise	E_E3 V 0 V- 0 1	
E_En VIN+ EN 28 0 1	I_ISY V+ V- DC 675E-6	
D_D13 29 28 DN	*	
V_V9 29 0 0.14	*Common Mode Gain Stage	
R_R21 28 0 80	*Common Mode Gain Stage	
10_10_1	G_G5 V++ VC VCM VMID 177.83E-6	



FIGURE 49. SPICE NET LIST

## **Characterization vs Simulation Results**

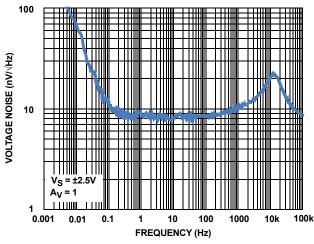


FIGURE 50. CHARACTERIZED INPUT NOISE VOLTAGE

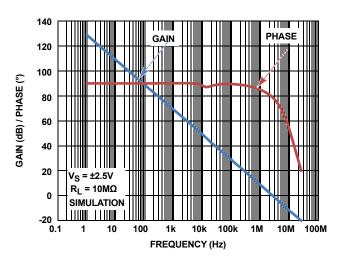


FIGURE 52. CHARACTERIZED OPEN-LOOP GAIN, PHASE vs FREQUENCY

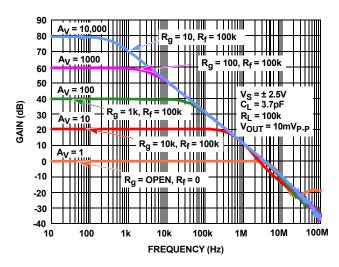


FIGURE 54. CHARACTERIZED CLOSED-LOOP GAIN vs FREQUENCY

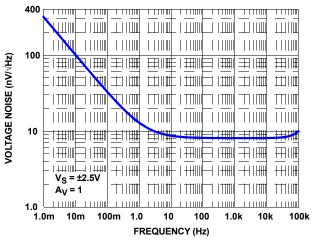


FIGURE 51. SIMULATED INPUT NOISE VOLTAGE

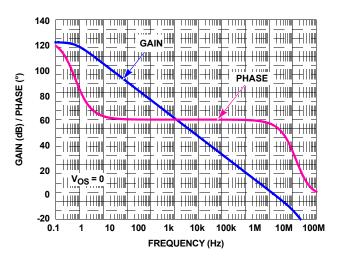


FIGURE 53. SIMULATED OPEN-LOOP GAIN, PHASE vs FREQUENCY

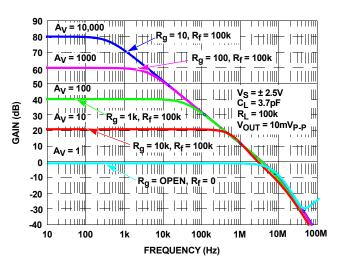


FIGURE 55. SIMULATED CLOSED-LOOP GAIN vs FREQUENCY

# **Characterization vs Simulation Results (Continued)**

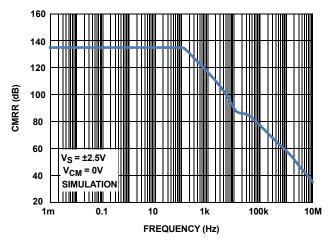
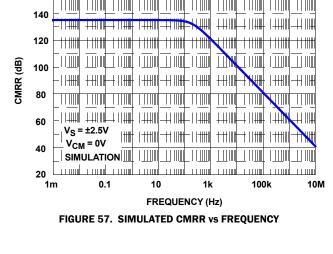


FIGURE 56. CHARACTERIZED CMRR vs FREQUENCY



160

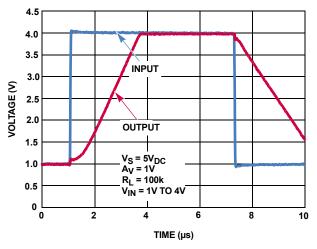


FIGURE 58. CHARACTERIZED LARGE SIGNAL STEP RESPONSE (3V)

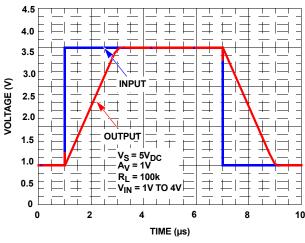


FIGURE 59. SIMULATED LARGE SIGNAL STEP RESPONSE (3V)

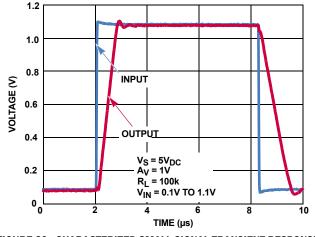


FIGURE 60. CHARACTERIZED SMALL-SIGNAL TRANSIENT RESPONSE

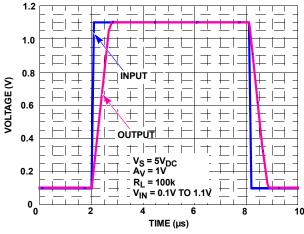


FIGURE 61. SIMULATED SMALL-SIGNAL TRANSIENT RESPONSE

# Characterization vs Simulation Results (Continued)

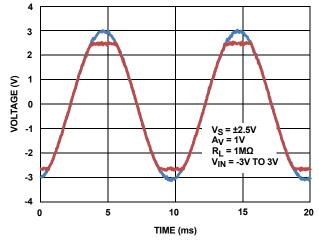


FIGURE 62. CHARACTERIZED NO PHASE INVERSION

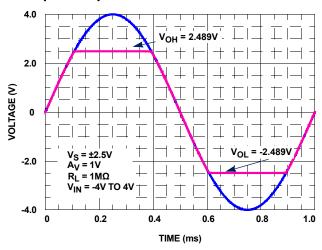


FIGURE 63. SIMULATED NO PHASE INVERSION,  $V_{\mbox{OH}}$  and  $V_{\mbox{OL}}$ 

# **Revision History**

The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to web to make sure you have the latest revision

DATE	REVISION	CHANGE
Mar 12, 2020	6.01	Updated Title Updated links throughout. Updated Related Literature. Updated Figures 1, 44, 45, 46, and 47. Updated Pin Configuration diagrams and circuits in Pin Description table. Updated Functional Description and High Source Impedance Applications sections. Removed About Intersil section. Updated disclaimer.
Oct 14, 2014	6.00	Figure 44 updated from: R <sub>s</sub> //R <sub>g</sub> = R <sub>S</sub> //R <sub>g</sub> to: R <sub>F</sub> //R <sub>l</sub> = R <sub>S</sub> //R <sub>g</sub> .  Removed part numbers ISL28134FRUZ-T7 and ISL28134FBZ from ordering information table.  Removed 6 LD UTDFN throughout the document.  Removed pod L6.1.6x1.6.
Jul 3, 2013	5.00	Updated the figure 1 on page 1, and changed title from "PRECISION 10-BIT WEIGH SCALE/STRAIN GAUGE" to "PRECISION WEIGH SCALE / STRAIN GAUGE".  Updated Figure 21: "Input noise voltage density vs frequency" on page 10.  Added typical EMIRR spec to Electrical Spec table under section "AC SPECIFICATIONS" on page 5.  Added applications paragraph to "EMI Rejection" on page 15.  Added 2 Figures, 33 and 46, describing the test circuit and typical performance graph for "EMI Rejection" on page 15.
Aug 3, 2012	4.00	Made correction to Figure 1 on page 1 by changing resistor label from "1M $\Omega$ " to "20k $\Omega$ ".
Dec 12, 2011	3.00	Updated front page introduction to reflect +125°C grade and SOT-23 package release.  Updated Figure 1 with newer relevant Apps Circuit  Updated Figure 2 with extended temp range -40°C to 125°C  Updated "Ordering Information" on page 3 by removing "Coming Soon" from ISL28134FHZ SOT-23 packages  Updated "Operating Conditions" on page 4 to include Full Industrial Grade Package.  Updated "Electrical Specifications" Tables for both Vs = 5V and Vs = 2.5V (page 4 to page 7) as follows:  Modified common conditions at top of tables from "Boldface limits apply over the operating  temperature range, -40°C to +85°C." to "Boldface limits apply over the specified operating temperature range.  Added MIN/MAX Vos spec from -40°C to 125°C: ±4μV  Updated Conditions cell for TCVos from +85°C to +125°C. No limit change.  Added MIN/MAX lbias spec from -40°C to 125°C: ±550pA  Added Typ TClbias spec from -40°C to 125°C: ±2pA/C  Added MIN/MAX los spec from -40°C to 125°C: ±2pA/C  Updated Conditions cell for Common Mode Input Voltage Range Spec (removed T <sub>A</sub> = -40°C to +85°C). No limit change.  Updated Conditions cell for CMRR for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for PSRR for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VO (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VO (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VOL for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VOL for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VOL for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VOL for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions cell for VOL for over temp (bolded) specs (removed T <sub>A</sub> = -40°C to +85°C). No limit change  Updated Conditions



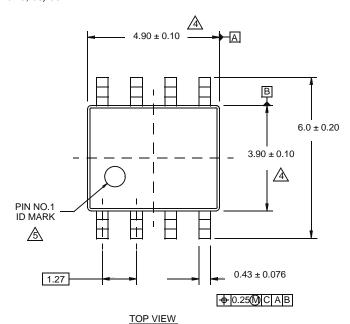
The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to web to make sure you have the latest revision. (Continued)

DATE	REVISION	CHANGE
Jul 6, 2011	2.00	Added Evaluation board to "Ordering Information" on page 3.  Updated "INPUT NOISE VOLTAGE DENSITY vs FREQUENCY" on page 10 (Changed MIN frequency from 100mHz to 1mHz)  Updated "LARGE SIGNAL STEP RESPONSE (3V)" on page 13 by changing the Time from 0 to 10 to 0 to 20 Added "ISL28134 SPICE Model" section, which includes Schematic, Macromodel and Characterization vs Simulation Results.
Jun 8, 2011	1.00	Initial release to web.

# **Package Outline Drawings**

For the most recent package outline drawing, see M8.15E.

M8.15E 8 LEAD NARROW BODY SMALL OUTLINE PLASTIC PACKAGE Rev 0, 08/09

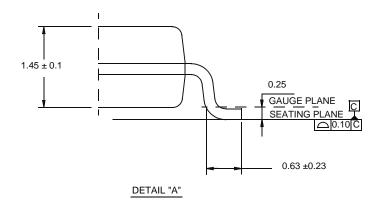


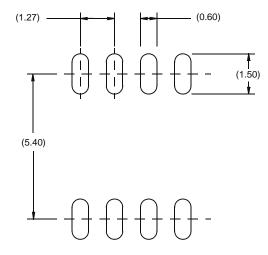
0.22 ± 0.03

(0.35) × 45°

SIDE VIEW "B"

1.75 MAX
0.175 ± 0.075
SIDE VIEW "A



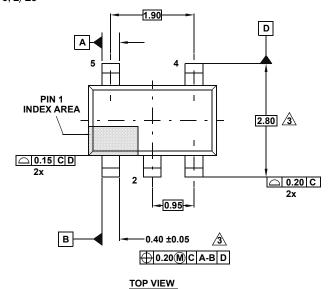


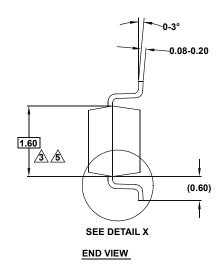
TYPICAL RECOMMENDED LAND PATTERN

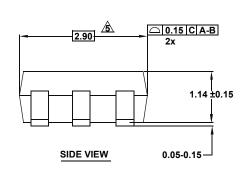
#### NOTES:

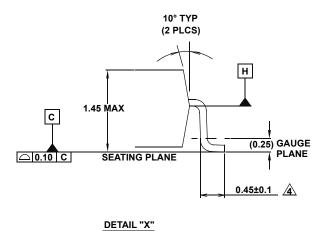
- Dimensions are in millimeters.
   Dimensions in ( ) for Reference Only.
- 2. Dimensioning and tolerancing conform to AMSE Y14.5m-1994.
- 3. Unless otherwise specified, tolerance : Decimal  $\pm 0.05$
- Dimension does not include interlead flash or protrusions.
   Interlead flash or protrusions shall not exceed 0.25mm per side.
- 5. The pin #1 identifier may be either a mold or mark feature.
- 6. Reference to JEDEC MS-012.

P5.064A 5 LEAD SMALL OUTLINE TRANSISTOR PLASTIC PACKAGE Rev 0, 2/10 For the most recent package outline drawing, see P5.064A.









(2.40)

(2.40)

(2.40)

(2.40)

(3.40)

(4.90)

TYPICAL RECOMMENDED LAND PATTERN

#### NOTES:

- Dimensions are in millimeters.
   Dimensions in ( ) for Reference Only.
- 2. Dimensioning and tolerancing conform to ASME Y14.5M-1994.
- 3 Dimension is exclusive of mold flash, protrusions or gate burrs.
- 4. Foot length is measured at reference to guage plane.
- 5. This dimension is measured at Datum "H".
- 6. Package conforms to JEDEC MO-178AA.

## **Notice**

- Descriptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products
  and application examples. You are fully responsible for the incorporation or any other use of the circuits, software, and information in the design of your
  product or system. Renesas Electronics disclaims any and all liability for any losses and damages incurred by you or third parties arising from the use of
  these circuits, software, or information.
- 2. Renesas Electronics hereby expressly disclaims any warranties against and liability for infringement or any other claims involving patents, copyrights, or other intellectual property rights of third parties, by or arising from the use of Renesas Electronics products or technical information described in this document, including but not limited to, the product data, drawings, charts, programs, algorithms, and application examples.
- No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
- 4. You shall not alter, modify, copy, or reverse engineer any Renesas Electronics product, whether in whole or in part. Renesas Electronics disclaims any and all liability for any losses or damages incurred by you or third parties arising from such alteration, modification, copying or reverse engineering.
- 5. Renesas Electronics products are classified according to the following two quality grades: "Standard" and "High Quality". The intended applications for each Renesas Electronics product depends on the product's quality grade, as indicated below.
  - "Standard": Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment; industrial robots; etc.
  - "High Quality": Transportation equipment (automobiles, trains, ships, etc.); traffic control (traffic lights); large-scale communication equipment; key financial terminal systems; safety control equipment; etc.

Unless expressly designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not intended or authorized for use in products or systems that may pose a direct threat to human life or bodily injury (artificial life support devices or systems; surgical implantations; etc.), or may cause serious property damage (space system; undersea repeaters; nuclear power control systems; aircraft control systems; military equipment; etc.). Renesas Electronics disclaims any and all liability for any damages or losses incurred by you or any third parties arising from the use of any Renesas Electronics product that is inconsistent with any Renesas Electronics data sheet, user's manual or other Renesas Electronics document.

- 6. When using Renesas Electronics products, refer to the latest product information (data sheets, user's manuals, application notes, "General Notes for Handling and Using Semiconductor Devices" in the reliability handbook, etc.), and ensure that usage conditions are within the ranges specified by Renesas Electronics with respect to maximum ratings, operating power supply voltage range, heat dissipation characteristics, installation, etc. Renesas Electronics disclaims any and all liability for any malfunctions, failure or accident arising out of the use of Renesas Electronics products outside of such specified ranges.
- 7. Although Renesas Electronics endeavors to improve the quality and reliability of Renesas Electronics products, semiconductor products have specific characteristics, such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Unless designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not subject to radiation resistance design. You are responsible for implementing safety measures to guard against the possibility of bodily injury, injury or damage caused by fire, and/or danger to the public in the event of a failure or malfunction of Renesas Electronics products, such as safety design for hardware and software, including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult and impractical, you are responsible for evaluating the safety of the final products or systems manufactured by you.
- 8. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. You are responsible for carefully and sufficiently investigating applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive, and using Renesas Electronics products in compliance with all these applicable laws and regulations. Renesas Electronics disclaims any and all liability for damages or losses occurring as a result of your noncompliance with applicable laws and regulations.
- 9. Renesas Electronics products and technologies shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations. You shall comply with any applicable export control laws and regulations promulgated and administered by the governments of any countries asserting jurisdiction over the parties or transactions.
- 10. It is the responsibility of the buyer or distributor of Renesas Electronics products, or any other party who distributes, disposes of, or otherwise sells or transfers the product to a third party, to notify such third party in advance of the contents and conditions set forth in this document.
- 11. This document shall not be reprinted, reproduced or duplicated in any form, in whole or in part, without prior written consent of Renesas Electronics.
- 12. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products.
- (Note1) "Renesas Electronics" as used in this document means Renesas Electronics Corporation and also includes its directly or indirectly controlled subsidiaries.
- (Note2) "Renesas Electronics product(s)" means any product developed or manufactured by or for Renesas Electronics.

(Rev.4.0-1 November 2017)

## **Corporate Headquarters**

TOYOSU FORESIA, 3-2-24 Toyosu, Koto-ku, Tokyo 135-0061, Japan www.renesas.com

#### **Trademarks**

Renesas and the Renesas logo are trademarks of Renesas Electronics Corporation. All trademarks and registered trademarks are the property of their respective owners.

## **Contact Information**

For further information on a product, technology, the most up-to-date version of a document, or your nearest sales office, please visit: www.renesas.com/contact/